

Important notice

Dear Customer,

On 7 February 2017 the former NXP Standard Product business became a new company with the tradename **Nexperia**. Nexperia is an industry leading supplier of Discrete, Logic and PowerMOS semiconductors with its focus on the automotive, industrial, computing, consumer and wearable application markets

In data sheets and application notes which still contain NXP or Philips Semiconductors references, use the references to Nexperia, as shown below.

Instead of http://www.nxp.com, http://www.nxp.com, http://www.nexperia.com/, use http://www.nexperia.com/

Instead of sales.addresses@www.nxp.com or sales.addresses@www.semiconductors.philips.com, use salesaddresses@nexperia.com (email)

Replace the copyright notice at the bottom of each page or elsewhere in the document, depending on the version, as shown below:

- © NXP N.V. (year). All rights reserved or © Koninklijke Philips Electronics N.V. (year). All rights reserved

Should be replaced with:

- © Nexperia B.V. (year). All rights reserved.

If you have any questions related to the data sheet, please contact our nearest sales office via e-mail or telephone (details via **salesaddresses@nexperia.com**). Thank you for your cooperation and understanding,

Kind regards,

Team Nexperia

PH3230S

N-channel TrenchMOS intermediate level FET

Rev. 04 — 27 November 2009

Product data sheet

1. Product profile

1.1 General description

Intermediate level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Saves PCB space due to small footprint
- Simple gate drive required due to low gate charge
- Suitable for logic level gate drive sources

1.3 Applications

- Computer motherboards
- DC-to-DC convertors

- Notebook computers
- Switched-mode power supplies

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}$	-	-	30	V
I_D	drain current	$T_{mb} = 25 \text{ °C}; V_{GS} = 10 \text{ V};$ see <u>Figure 1</u> and <u>3</u>	-	-	100	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	62.5	W
Dynamic	characteristics					
Q_{GD}	gate-drain charge	$V_{GS} = 5 \text{ V}; I_D = 50 \text{ A};$ $V_{DS} = 10 \text{ V}; T_j = 25 \text{ °C};$ see Figure 12	-	13	-	nC
Static ch	aracteristics					
R_{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C};$ see Figure 9 and 10	-	2.7	3.2	mΩ



N-channel TrenchMOS intermediate level FET

2 of 12

Pinning information 2.

Table 2. **Pinning information**

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		
2	S	source	mb	D
3	S	source		
4	G	gate	9	
mb	D	mounting base; connected to drain	1 2 3 4	mbb076 Ś
			SOT669 (LFPAK)	

Ordering information 3.

Table 3. **Ordering information**

Type number	Package		
	Name	Description	Version
PH3230S	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669

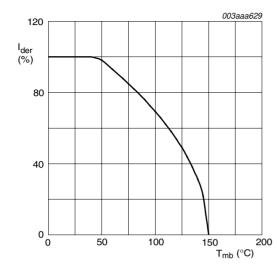
Limiting values

Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}$	-	30	V
V_{GS}	gate-source voltage		-20	20	V
I_D	drain current	$V_{GS} = 10 \text{ V}$; $T_{mb} = 25 \text{ °C}$; see <u>Figure 1</u> and <u>3</u>	-	100	Α
		V _{GS} = 10 V; T _{mb} = 100 °C; see <u>Figure 1</u>	-	63	Α
I _{DM}	peak drain current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$; see Figure 3	-	300	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	62.5	W
T _{stg}	storage temperature		-55	150	°C
Tj	junction temperature		-55	150	°C
Source-dra	ain diode				
Is	source current	T _{mb} = 25 °C	-	52	Α
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	156	Α
Avalanche	ruggedness				
$E_{DS(AL)R}$	repetitive drain-source avalanche energy	$V_{GS} = 10 \text{ V}; I_D = 5 \text{ A}; V_{sup} = 15 \text{ V}; R_{GS} \ge 50 \Omega$	-	2.5	mJ
$E_{DS(AL)S}$	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 50 A; V_{sup} ≤ 15 V; unclamped; R_{GS} = 50 Ω	-	250	mJ

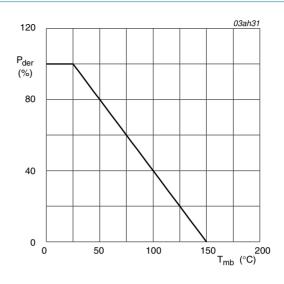
N-channel TrenchMOS intermediate level FET



$$V_{GS} \ge 10VI_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100\%$$

Normalized continuous drain current as a Fig 1. function of mounting base temperature

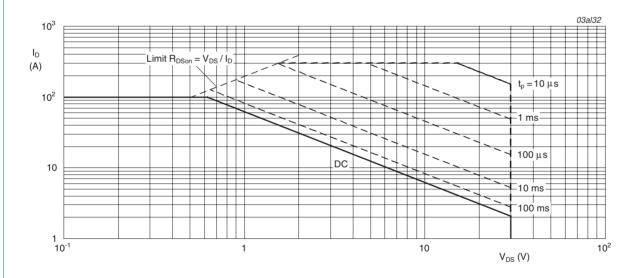
Product data sheet



$$P_{der} = \frac{P(tot)}{P_{tot(25^{\circ}C)}} \times 100\%$$

3 of 12

Normalized total power dissipation as a Fig 2. function of mounting base temperature



 $T_{mb} = 25$ °C; I_{DM} is single pulse

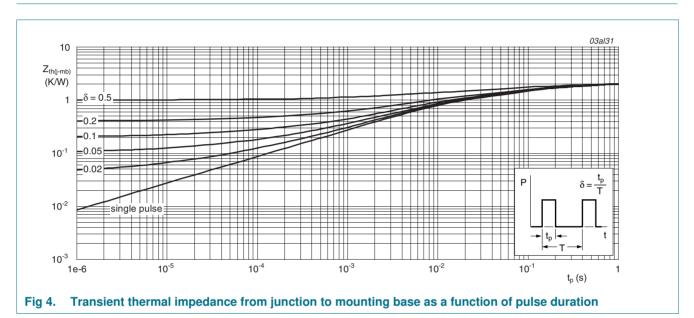
Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

N-channel TrenchMOS intermediate level FET

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	2	K/W



N-channel TrenchMOS intermediate level FET

6. Characteristics

Table 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 10 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	30	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 25$ °C; see Figure 8	1	2	3	V
I _{DSS}	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μΑ
I _{GSS}	gate leakage current	$V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	100	nA
		$V_{GS} = -20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	100	nΑ
200	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C};$ see <u>Figure 9</u>	-	5	6.5	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C};$ see Figure 9 and 10	-	2.7	3.2	mΩ
Source-d	rain diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C};$ see <u>Figure 11</u>	-	8.0	1.2	V
t _{rr}	reverse recovery time	I_S = 20 A; dI_S/dt = -50 A/ μ s; V_{GS} = 0 V; V_{DS} = 25 V; T_j = 25 °C	-	46	-	ns
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 50 \text{ A}; V_{DS} = 10 \text{ V}; V_{GS} = 5 \text{ V};$	-	42	-	nC
Q_{GS}	gate-source charge	$T_j = 25 ^{\circ}\text{C}$; see Figure 12	-	21	-	nC
Q_{GD}	gate-drain charge		-	13	-	nC
C _{iss}	input capacitance	$V_{DS} = 10 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$	-	4100	-	pF
Coss	output capacitance	T _j = 25 °C; see <u>Figure 13</u>	-	1150	-	рF
C _{rss}	reverse transfer capacitance		-	750	-	pF
t _{d(on)}	turn-on delay time	V_{DS} = 10 V; R_L = 0.4 Ω ; V_{GS} = 10 V;	-	14	-	ns
t _r	rise time	$R_{G(ext)} = 4.7 \Omega; T_j = 25 \text{ °C}$	-	37	-	ns
t _{d(off)}	turn-off delay time		-	85	-	ns
t _f	fall time		-	37	-	ns
9 _{fs}	transfer conductance	$V_{DS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C};$ see <u>Figure 14</u>	39	75	-	S

N-channel TrenchMOS intermediate level FET

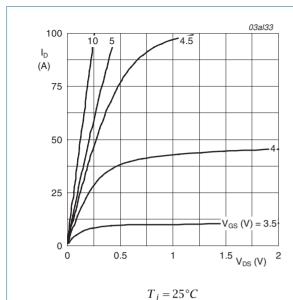
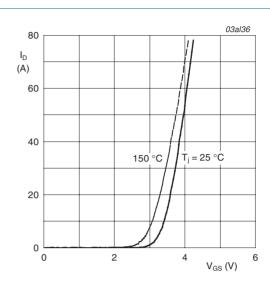


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values



 $T_j = 25$ °C and 150°C; $V_{DS} > I_D \times R_{DSon}$

Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values

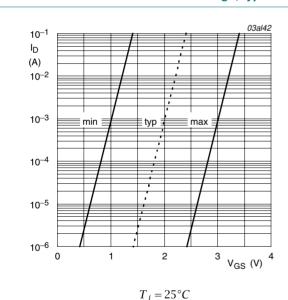
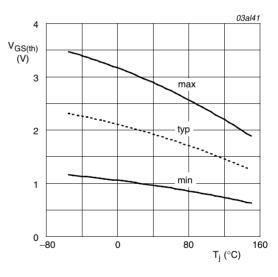


Fig 7. Sub-threshold drain current as a function of gate-source voltage



 $I_D = 1mA; V_{DS} = V_{GS}$

Gate-source threshold voltage as a function of Fig 8. junction temperature

N-channel TrenchMOS intermediate level FET

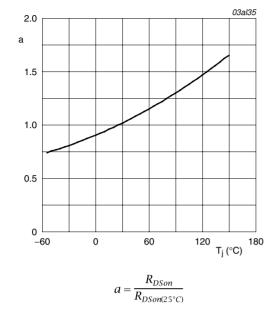
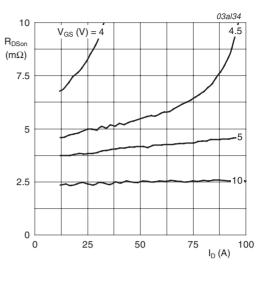


Fig 9. Normalized drain-source on-state resistance factor as a function of junction temperature



 $T_i = 25^{\circ}C$

Fig 10. Drain-source on-state resistance as a function of drain current; typical values

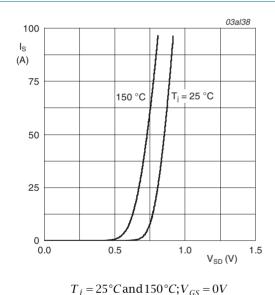
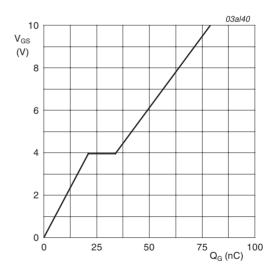


Fig 11. Source current as a function of source-drain

voltage; typical values



 $T_j = 25$ °C; $I_D = 50A$; $V_{DD} = 10V$

Fig 12. Gate-source voltage as a function of gate charge; typical values

N-channel TrenchMOS intermediate level FET

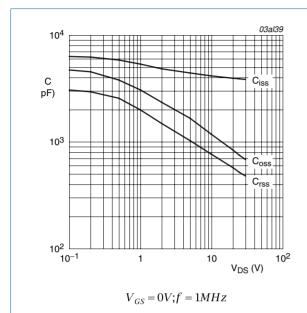


Fig 13. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

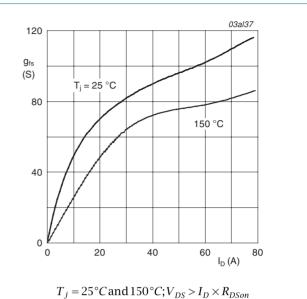


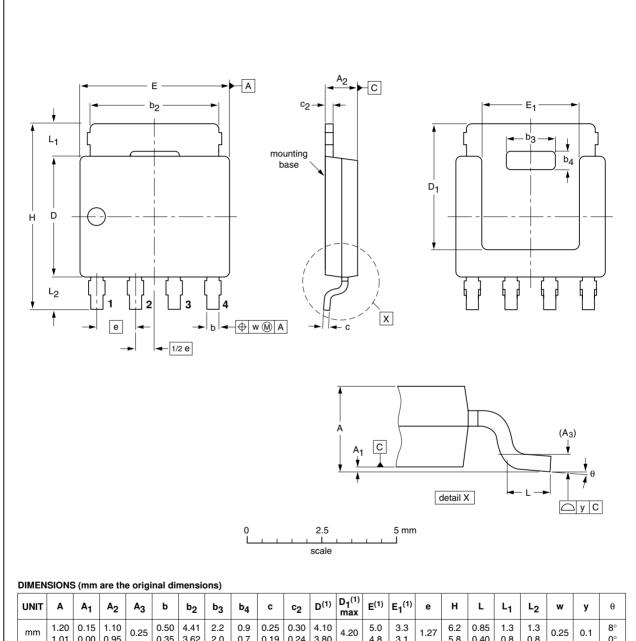
Fig 14. Forward transconductance as a function of drain current; typical values

8 of 12

Package outline

Plastic single-ended surface-mounted package (LFPAK); 4 leads

SOT669



UN	IT .	A	A ₁	A ₂	A ₃	b	b ₂	b ₃	b ₄	С	c ₂	D ⁽¹⁾	D ₁ ⁽¹⁾ max	E ⁽¹⁾	E ₁ ⁽¹⁾	е	Н	L	L ₁	L ₂	w	у	θ
mr	n ı	- 1	0.15 0.00	1.10 0.95	0.25	0.50 0.35	4.41 3.62	2.2 2.0	0.9 0.7	0.25 0.19		4.10 3.80	4.20	5.0 4.8	3.3 3.1	1.27	6.2 5.8	0.85 0.40	1.3 0.8	1.3 0.8	0.25	0.1	8° 0°

Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT669		MO-235			04-10-13 06-03-16

Fig 15. Package outline SOT669 (LFPAK)

© NXP B.V. 2009. All rights reserved.

N-channel TrenchMOS intermediate level FET

10 of 12

Revision history

Table 7. **Revision history**

Product data sheet

•			
Release date	Data sheet status	Change notice	Supersedes
20091127	Product data sheet	-	PH3230S-03
		en redesigned to compl	y with the new identity
 Legal texts 	have been adapted to the	new company name v	vhere appropriate.
20040302	Product data	-	PH3230S-02
20030423	Product data	-	PH3230S-01
20030212	Preliminary data	-	-
	20091127 • The format guidelines • Legal texts 20040302 20030423	 20091127 Product data sheet The format of this data sheet has bee guidelines of NXP Semiconductors. Legal texts have been adapted to the 20040302 Product data 20030423 Product data 	Product data sheet The format of this data sheet has been redesigned to compliguidelines of NXP Semiconductors. Legal texts have been adapted to the new company name version of the semiconduct of the new company name version of the semiconduct of the new company name version of the semiconduct of the new company name version of the semiconduct of the new company name version of the semiconduct of the new company name version of the semiconduct of the new company name version of the semiconduct of the new company name version of the semiconduct of the new company name version of the new

N-channel TrenchMOS intermediate level FET

9. Legal information

9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URLhttp://www.nxp.com.

9.2 Definitions

Draft— The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Short data sheet— A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local NXP Semiconductors sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

9.3 Disclaimers

General— Information in this document is believed to be accurate and reliable. However, NXP Semiconductors does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information.

Right to make changes— NXP Semiconductors reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use— NXP Semiconductors products are not designed, authorized or warranted to be suitable for use in medical, military, aircraft, space or life support equipment, nor in applications where failure or malfunction of an NXP Semiconductors product can reasonably be expected to result in personal injury, death or severe property or environmental damage. NXP Semiconductors accepts no liability for inclusion and/or use of NXP Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

Applications— Applications that are described herein for any of these products are for illustrative purposes only. NXP Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Quick reference data— The Quick reference data is an extract of the product data given in the Limiting values and Characteristics sections of this document, and as such is not complete, exhaustive or legally binding.

Limiting values— Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) may cause permanent damage to the device. Limiting values are stress ratings only and operation of the device at these or any other conditions above those given in the Characteristics sections of this document is not implied. Exposure to limiting values for extended periods may affect device reliability.

Terms and conditions of sale— NXP Semiconductors products are sold subject to the general terms and conditions of commercial sale, as published at http://www.nxp.com/profile/terms, including those pertaining to warranty, intellectual property rights infringement and limitation of liability, unless explicitly otherwise agreed to in writing by NXP Semiconductors. In case of any inconsistency or conflict between information in this document and such terms and conditions, the latter will prevail.

No offer to sell or license— Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

Export control— This document as well as the item(s) described herein may be subject to export control regulations. Export might require a prior authorization from national authorities.

9.4 Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

TrenchMOS— is a trademark of NXP B.V.

10. Contact information

For more information, please visit:http://www.nxp.com

For sales office addresses, please send an email to:salesaddresses@nxp.com

PH3230S_4 © NXP B.V. 2009. All rights reserved.

PH3230S NXP Semiconductors

N-channel TrenchMOS intermediate level FET

11. Contents

1	Product profile	1
1.1	General description	1
1.2	Features and benefits	1
1.3	Applications	1
1.4	Quick reference data	1
2	Pinning information	2
3	Ordering information	2
4	Limiting values	2
5	Thermal characteristics	4
6	Characteristics	5
7	Package outline	9
8	Revision history10	0
9	Legal information1	1
9.1	Data sheet status	1
9.2	Definitions1	
9.3	Disclaimers	1
9.4	Trademarks1	
10	Contact information 1:	1

Please be aware that important notices concerning this document and the product(s) described herein, have been included in section 'Legal information'.





© NXP B.V. 2009. All rights reserved.

For more information, please visit: http://www.nxp.com For sales office addresses, please send an email to: salesaddresses@nxp.com

Date of release: 27 November 2009 Document identifier: PH3230S_4